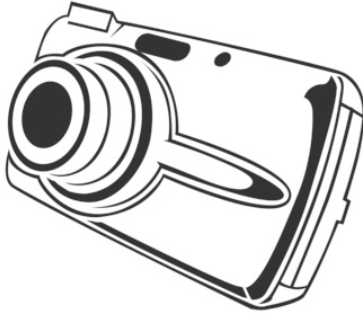


**NO IMAGE**



## High resolution electrostatic force microscopy

High aspect ratio probe tip with conductive Pt coating on tip side.

### Tip Apex Specifications

Radius after coating :	< 25 nm
Full cone angle:	~ 12°
Tip height:	> 9 μm

### Available Cantilevers:

C = 40 N/m, fo = 300 kHz
C = 3.0 N/m, fo = 75 kHz
C = 0.7 N/m, fo = 45 kHz

Standard coating on backside of cantilever is Aluminium.  
Please contact us if you do not need reflex coating.

1 pack includes 5 probe-tips

Probe tips, cantilevers, and cantilever chips consist of single crystal silicon.

All cantilevers are shipped with Al-reflex coating (R).  
The HR-EFM probes are also available with alignment grooves on the back side of the holder chip.  
Shipments without reflex coating or with special coatings upon request.

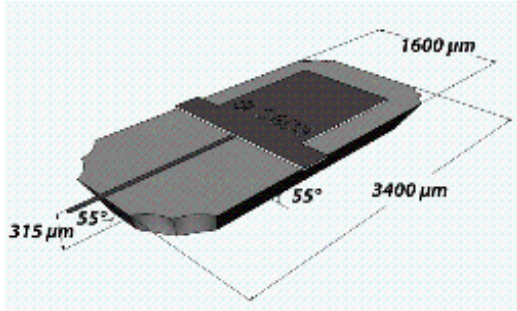
All probe tips are SEM quality inspected prior to shipment.

### Cantilever Dimensions:

Stiffness	Typical resonant frequency	Length	Width
40 N/m	300 kHz	125 (± 15) μm	35 (± 3) μm
3.0 N/m	75 kHz	225 (± 15) μm	35 (± 3) μm
0.7 N/m	45 kHz	225 (± 15) μm	35 (± 3) μm

### Holder chip dimensions:

Length	3.40 mm
Width	1.55 mm
Thickness	0.315 mm



EFM Lever: C = 40 N/m, C = 3.0 N/m, C = 0.7 N/m

ReflexCoating: Al-reflex